

Bias-Induced threshold voltage shifts in organic thin-film transistors by soluble fullerene layers on gate dielectric

Abstract

An investigation of threshold voltage shifts in organic thin-film transistors (TFTs) based on pentacene with an additional soluble fullerene derivatives of [6,6]-phenyl C(61)-butyric acid methyl ester (PCBM) on gate dielectric. With an additional soluble fullerene layer, the threshold voltage (V_{th}) is optimized from -3: 9 to -1:1 V without affect the mode operation of the devices, while retaining the carrier mobility ($0.02-0.03 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$) and on/off current ratio (similar to 10^4). Furthermore, the existence of PCBM agglomerates as electron acceptor-like traps resulted in a shift of V_{th} in the positive and reversible directions depending on the magnitude of gate bias (V_{bias}) as well as duration of time bias (T_{bias}). The device operation changed into normally-on (depletion-accumulation) mode upon positive V_{bias} as the duration of T_{bias} was increased, which attributes to the formation of a conductive layer at the pentacene-fullerene interface. Moreover, the recovery of V_{th} was further enhanced by a high negative V_{bias} for a short duration. In addition, the mobility was minimally affected by both V_{bias} conditions. (C) 2011 The Japan Society of Applied Physics